TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# TC74ACT157P, TC74ACT157F, TC74ACT157FN, TC74ACT157FT

1

#### OUAD 2 - CHANNEL MULTIPLEXER

The TC74ACT157 is an advanced high speed CMOS QUAD 2 - CHANNEL MULTIPLEXER fabricated with silicon gate and double-layer metal wiring C2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL,NMOS and CMOS output voltage levles. This device consist of four 2-input digital multiplexer with common select and strobe inputs.

When the STROBE input is held "H" level, selection of data is inhibited and all the outputs become "L" level.

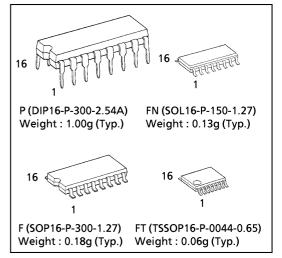
The SELECT decoding determines whether the A or B inputs get routed to their corresponding Y outputs.

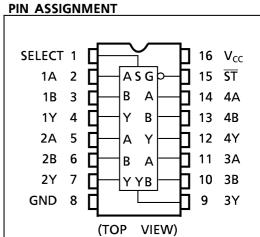
All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### FEATURES:

- High Speed------ $t_{pd} = 5.1 \text{ns}(typ.)$  at  $V_{CC} = 5V$
- Compatible with TTL outputs  $\cdots V_{IL} = 0.8V(Max.)$  $V_{IH} = 2.0V(Min.)$
- Symmetrical Output Impedance  $|I_{OH}| = I_{OL} = 24$ mA(Min.) Capability of driving  $50\Omega$ tansmission lines.
- Balanced Propagation Delays ····· t<sub>pLH</sub> ≃ t<sub>pHL</sub>
- Pin and Function Compatible with 74F157

(Note) The JEDEC SOP (FN) is not available in Japan.



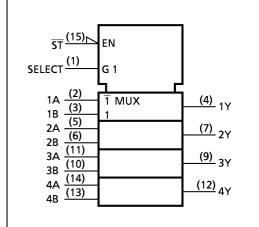


#### TRUTH TABLE

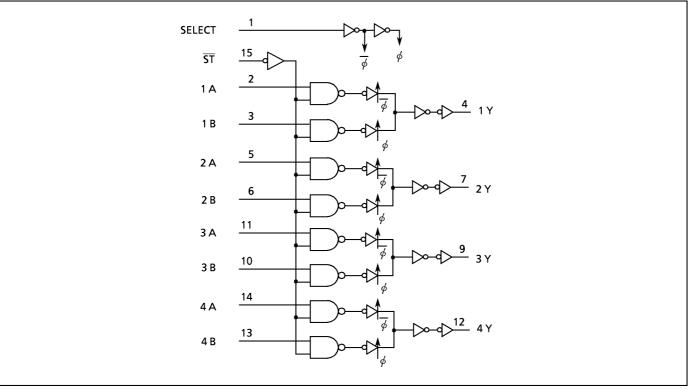
	OUTPUTS			
ST	SELECT	Α	В	Υ
Н	Х	Х	Х	L
L	L	L	Х	L
L	L	Н	Х	Н
L	Н	Х	L	L
L	Н	Х	Н	Н

X: Don't Care

**IEC LOGIC SYMBOL** 



### SYSTEM DIAGRAM



**ABSOLUTE MAXIMUM RATINGS** 

ABSOLUTE MAXIMUM RATINGS								
PARAMETER	SYMBOL	VALUE	UNIT					
Supply Voltage Range	V <sub>cc</sub>	-0.5~7.0	V					
DC Input Voltage	V <sub>IN</sub>	−0.5~V <sub>CC</sub> + 0.5	V					
DC Output Voltage	V <sub>OUT</sub>	$-0.5 \sim V_{CC} + 0.5$	V					
Input Diode Current	I <sub>IK</sub>	± 20	mΑ					
Output Diode Current	I <sub>OK</sub>	± 50	mΑ					
DC Output Current	I <sub>OUT</sub>	± 50	mΑ					
DC V <sub>cc</sub> /Ground Current	I <sub>cc</sub>	± 100	mΑ					
Power Dissipation	P <sub>D</sub>	500 (DIP)*/ 180 (SOP/TSSOP)	mW					
Storage Temperature	T <sub>stg</sub>	<b>−65~150</b>	°C					

\*500mW in the range of Ta =  $-40^{\circ}\text{C} \sim 65^{\circ}\text{C}$ . From Ta =  $65^{\circ}\text{C}$  to  $85^{\circ}\text{C}$  a derating factor of  $-10\text{mW}/^{\circ}\text{C}$  should be applied up to 300mW.

RECOMMENDED OPERATING CONDITIONS

RECOMMENDED OF ERATING	, <u> </u>	10113	
PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	$V_{cc}$	4.5~5.5	V
Input Voltage	V <sub>IN</sub>	0~V <sub>CC</sub>	V
Output Voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	V
Operating Temperature	T <sub>opr</sub>	<b>−40~85</b>	°C
Input Rise and Fall Time	dt/dV	0~10	ns / V

2 2001-05-17

#### DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION		V <sub>cc</sub>	Ta = 25°C		Ta = -40~85°C		UNIT	
PARAIVIETER	STIVIBUL			(V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High - Level Input Voltage	V <sub>IH</sub>			4.5 5.5	2.0	1	_	2.0	_	V
Low - Level Input Voltage	VIL			4.5 \$ 5.5	ı	-	0.8	_	0.8	<b>V</b>
High - Level Output Voltage	V <sub>OH</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -50 \mu A$ $I_{OH} = -24 m A$ $I_{OH} = -75 m A^*$	4.5 4.5 5.5	4.4 3.94 —	4.5 — —	_ 	4.4 3.80 3.85	_ _ _	٧
Low - Level Output Voltage	V <sub>OL</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 50 \mu A$ $I_{OL} = 24 m A$ $I_{OL} = 75 m A*$	4.5 4.5 5.5	111	0.0 — —	0.1 0.36 —	1 1 1	0.1 0.44 1.65	V
Input Leakage Current	I <sub>I N</sub>	$V_{IN} = V_{CC}$ or GND		5.5	1	1	± 0.1	_	± 1.0	
	I <sub>cc</sub>	$V_{IN} = V_{CC}$ or GND		5.5		_	8.0	Ė	80.0	μΑ
Quiescent Supply Current	I <sub>C</sub>	PER INPUT : V <sub>II</sub> OTHER INPUT	5.5	_	_	1.35	_	1.5	mA	

<sup>\* :</sup> This spec indicates the capability of driving  $50\Omega$  transmission lines. One output should be tested at a time for a 10ms maximum duration.

## AC ELECTRICAL CHARACTERISTICS ( $C_L = 50 pF$ , $R_L = 500 \Omega$ , Input $t_r = t_f = 3 ns$ )

PARAMETER	CVMPOL	TEST CONDITION		Ta = 25°C			Ta = −40~85°C		UNIT
FARAIVIETER	SYMBOL		$V_{cc}(V)$	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
Propagation Delay Time (A,B-Y)	t <sub>pLH</sub> t <sub>pHL</sub>		5.0 ± 0.5	_	5.5	8.0	1.0	9.1	
Propagation Delay Time (SELECT—Y)	t <sub>pLH</sub> t <sub>pHL</sub>		5.0 ± 0.5	_	6.9	11.4	1.0	13.0	ns
Propagation Delay Time $(\overline{ST} - Y)$	t <sub>pLH</sub> t <sub>pHL</sub>		5.0 ± 0.5	_	6.8	10.8	1.0	12.3	
Input Capacitance	C <sub>IN</sub>			_	5	10	_	10	ne
Power Dissipation Capacitance	C <sub>PD</sub>			_	51	_	_	_	pF

Note (1)  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

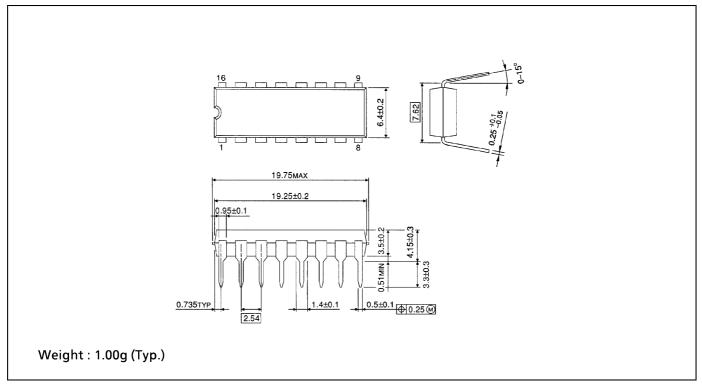
Average operating current can be obtained by the equation:

$$I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 4 (per bit)$$

3 2001-05-17

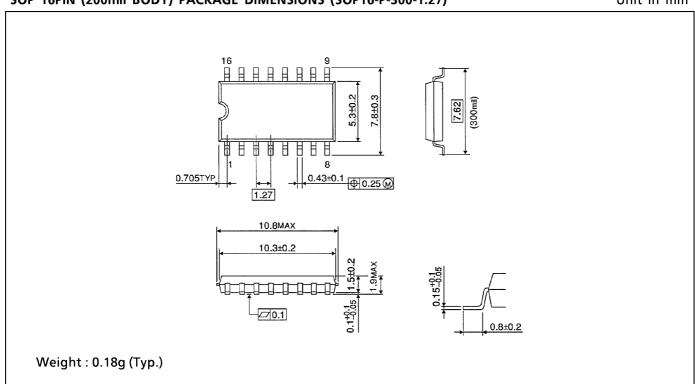
### DIP 16PIN PACKAGE DIMENSIONS (DIP16-P-300-2.54A)

Unit in mm



### SOP 16PIN (200mil BODY) PACKAGE DIMENSIONS (SOP16-P-300-1.27)

Unit in mm

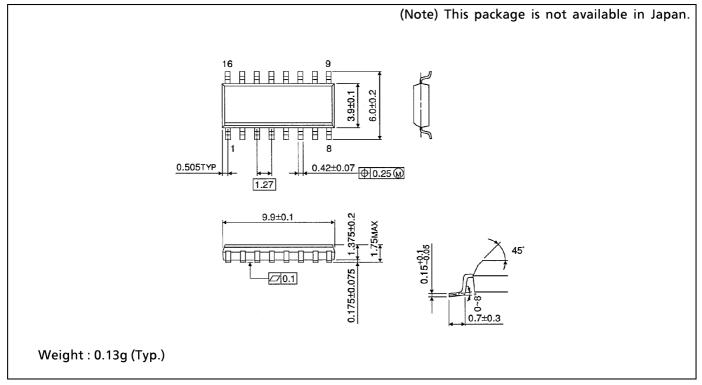


4

2001-05-17

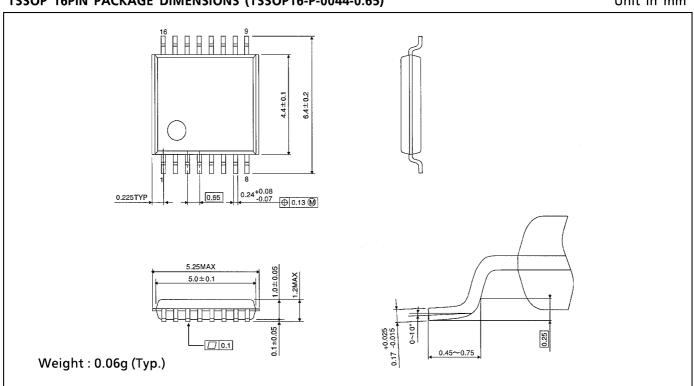
# SOP 16PIN (150mil BODY) PACKAGE DIMENSIONS (SOL16-P-150 -1.27)

Unit in mm



### TSSOP 16PIN PACKAGE DIMENSIONS (TSSOP16-P-0044-0.65)

Unit in mm



5 2001-05-17

#### **RESTRICTIONS ON PRODUCT USE**

000707EBA

- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- The products described in this document are subject to the foreign exchange and foreign trade laws.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others.
- The information contained herein is subject to change without notice.

6 2001-05-17